

**Search Notes**

Application/Control No.

10/549,615

Examiner

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Applicant(s)/Patent under  
Reexamination

HOSHINO ET AL.

Art Unit

2819

**SEARCHED**

Class	Subclass	Date	Examiner
375	340,341 335,265 207,267	1/13/2006	LN
370	252,335	1/13/2006	LN
370	270,331	1/13/2006	LN
714	702,755	1/13/2006	LN
341	50	1/13/2006	LN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East searched-see printout	1/13/2006	LN